- **Package Options Include Plastic Small Outline Packages, Ceramic Chip Carriers, and Standard Plastic and Ceramic 300-mil DIPs**
- **Dependable Texas instruments Quality and Reliability**

TYPE	TYPICAL MAXIMUM CLOCK FREQUENCY (C_L = 50 pF)	TYPICAL POWER DISSIPATION PER FLIP-FLOP
'ALS74A	50 MHz	6 mW
'AS74	134 MHz	26 mW

description

These devices contain two independent D-type positive-edge triggered flip-flops. A low level at the Preset or Clear inputs sets or resets the outputs regardless of the levels of the other inputs. When Preset and Clear are inactive (high), data at the D input meeting the setup time requirements are transferred to the outputs on the positive-going edge of the clock pulse. Clock triggering occurs at a voltage level and is not directly related to the rise time of the clock pulse. Following the hold time interval, data at the D input may be changed without affecting the levels at the outputs.

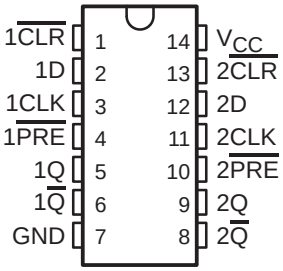
The SN54ALS74A and SN54AS74 are characterized for operation over the full military temperature range of –55°C to 125°C. The SN74ALS74A and SN74AS74 are characterized for operation from 0°C to 70°C.

FUNCTION TABLE

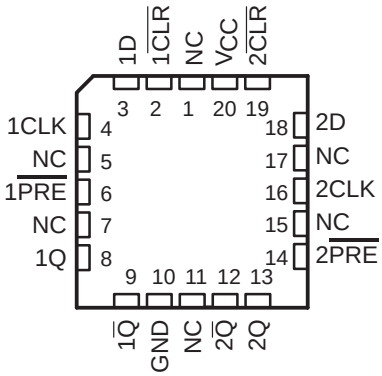
INPUTS				OUTPUTS	
PRESET	CLEAR	CLOCK	D	Q	$\overline{Q}$
L	H	X	X	H	L
H	L	X	X	L	H
L	L	X	X	H†	H†
H	H	↑	H	H	L
H	H	↑	L	L	H
H	H	L	X	Q_O	$\overline{Q}_O$

† The output levels in this configuration are not guaranteed to meet the minimum levels for V_{OH} if the lows at Preset and Clear are near V_{IL} maximum. Furthermore, this configuration is nonstable; that is, it will not persist when Preset or Clear; returns to their inactive (high) level.

SN54ALS74A, SN54AS74 . . . J PACKAGE
SN74ALS74A, SN74AS74 . . . D OR N PACKAGE
(TOP VIEW)

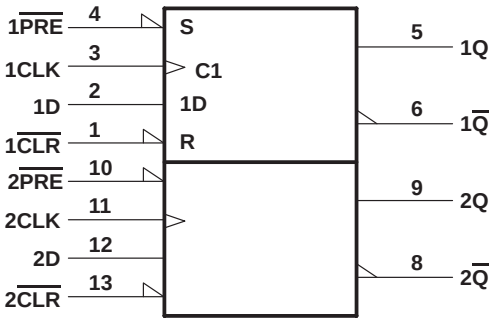


SN54ALS74A, SN54AS74 . . . FK PACKAGE
(TOP VIEW)



NC – No internal connection

logic symbol‡



‡ This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.
Pin numbers shown are for D, J, and N packages.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, V_{CC} . . . . . 7 V
Input voltage . . . . . 7 V
Operating free-air temperature range: SN54ALS74A, SN54ALS74 . . . . . –55°C to 125°C
SN74ALS74A, SN74ALS74 . . . . . 0°C to 70°C
Storage temperature range . . . . . –65°C to 150°C

recommended operating conditions

			SN54AS74			SN74AS74			UNIT
			MIN	NOM	MAX	MIN	NOM	MAX	
V_{CC}	Supply voltage		4.5	5	5.5	4.5	5	5.5	V
V_{IH}	High-level input voltage		2			2			V
V_{IL}	Low-level input voltage							0.8	V
					0.8†				
					0.7‡				
I_{OH}	High-level output current				–0.4			–0.4	mA
I_{OL}	Low-level output current				4			8	mA
f_{clock}	Clock frequency		0		25	0		34	MHz
t_w	Pulse duration	$\overline{PRE}$ or $\overline{CLR}$ low	15			15			ns
		CLK high	16.5			14.5			
		CLK low	16.5			14.5			
t_{su}	Setup time before CLK↑	Data	15			15			ns
		$\overline{PRE}$ or $\overline{CLR}$ inactive	10			10			
t_h	Hold time, data after CLK↑		0			0			ns
T_A	Operating free-air temperature		–55		125	0		70	°C

† Tested at –55°C to 70°C.
‡ Tested at 70°C 125°C, per MIL-STD-883, method 5005, sub-group 1, 2, and 3. Static tests are performed at 25°C, 125°C, and –55°C.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS		SN54AS74			SN74AS74			UNIT
				MIN	TYP§	MAX	MIN	TYP§	MAX	
V_{IK}		V_{CC} = 4.5 V,	I_I = –18 mA				–1.2		–1.5	V
V_{OH}		V_{CC} = 4.5 V to 5.5 V,	I_{OH} = –2mA	V_{CC}–2			V_{CC}–2			V
V_{OL}		V_{CC} = 4.5 V,	I_{OL} = 4 mA		0.25	0.4		0.25	0.4	V
V_{OL}		V_{CC} = 4.5 V,	I_{OL} = 8 mA					0.35	0.5	
I_I	CLK or D	V_{CC} = 4.5 V,	V_I = 7 V			0.1			0.1	mA
	$\overline{PRE}$ or $\overline{CLR}$					0.2			0.2	
I_{IH}	CLK or D	V_{CC} = 4.5 V,	V_I = 2.7 V			20			20	µA
	$\overline{PRE}$ or $\overline{CLR}$					40			40	
I_{IL}	CLK or D	V_{CC} = 4.5 V,	V_I = 0.4 V			–0.2			–0.2	mA
	$\overline{PRE}$ or $\overline{CLR}$					–0.4			–0.4	
I_O¶		V_{CC} = 5.5 V,	V_O = 2.25 V	–30		–112	–30		–112	mA
I_{CC}		V_{CC} = 5.5 V,	See Note 1		2.4	4		2.4	4	mA

§ All typical values are at V_{CC} = 5 V, T_A = 25°C.
¶ The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, I_{OS}.
NOTE 1: I_{CC} is measured with D, CLK, and $\overline{PRE}$ grounded, then with D, CLK, and $\overline{CLR}$ grounded.

switching characteristics (see Note 2)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V_{CC} = 4.5 V to 5.5 V, C_L = 50 pF, R_L = 500 Ω, T_A = MIN TO MAX†				UNIT
			SN54ALS74A		SN74ALS74A		
			MIN	MAX	MIN	MAX	
f_{max}			25		34		MHz
t_{PLH}	$\overline{PRE}$ or $\overline{CLR}$	Q or $\overline{Q}$	3	13.5	3	13	ns
t_{PHL}			5	17	5	15	
t_{PLH}	CLK	Q or $\overline{Q}$	5	17	5	16	ns
t_{PHL}			5	18	5	18	

† For conditions shown MIN or MAX, use the appropriate value specified under recommended operating conditions.
NOTE 2: Load circuit and voltage waveforms are shown in Section 1 of the *ALS/AS Logic Data Book*, 1986.

recommended operating conditions

			SN54AS74			SN74AS74			UNIT
			MIN	NOM	MAX	MIN	NOM	MAX	
V_{CC}	Supply voltage		4.5	5	5.5	4.5	5	5.5	V
V_{IH}	High-level input voltage		2			2			V
V_{IL}	Low-level input voltage				0.8			0.8	V
I_{OH}	High-level output current				–2			–2	mA
I_{OL}	Low-level output current				20			20	mA
f_{clock}	Clock frequency		0		90	0		105	MHz
t_w	Pulse duration	$\overline{PRE}$ or $\overline{CLR}$ low	4			4			ns
		CLK high	4			4			
		CLK low	5.5			5.5			
t_{su}	Setup time before CLK↑	Data	4.5			4.5			ns
		$\overline{PRE}$ or $\overline{CLR}$ inactive	2			2			
t_h	Hold time, data after CLK↑		0			0			ns
T_A	Operating free-air temperature		–55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS		SN54AS74			SN74AS74			UNIT
				MIN	TYP†	MAX	MIN	TYP†	MAX	
V_{IK}		V_{CC} = 4.5 V,	I_I = –18 mA				–1.2		–1.2	V
V_{OH}		V_{CC} = 4.5 V to 5.5 V,	I_{OH} = –2mA	V_{CC}–2			V_{CC}–2			V
V_{OL}		V_{CC} = 4.5 V,	I_{OL} = 20 mA		0.25	0.5		0.25	0.5	V
I_I		V_{CC} = 5.5 V,	V_I = 7 V			0.1			0.1	mA
I_{IH}	CLK or D	V_{CC} = 5.5 V,	V_I = 2.7 V			20			20	µA
	$\overline{PRE}$ or $\overline{CLR}$					40			40	
I_{IL}	CLK or D	V_{CC} = 5.5 V,	V_I = 0.4 V			–0.5			–0.5	mA
	$\overline{PRE}$ or $\overline{CLR}$					–1.8			–1.8	
I_O‡		V_{CC} = 5.5 V,	V_O = 2.25 V	–30		–112	–30		–112	mA
I_{CC}		V_{CC} = 5.5 V,	See Note 1		10.5	16		10.5	16	mA

† All typical values are at V_{CC} = 5 V, T_A = 25°C.
‡ The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, I_{OS}.
NOTE 1: I_{CC} is measured with D, CLK, and $\overline{PRE}$ grounded, then with D, CLK, and $\overline{CLR}$ grounded.

switching characteristics (see Note 2)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V_{CC} = 4.5 V to 5.5 V, C_L = 50 pF, R_L = 500 Ω, T_A = MIN TO MAX§				UNIT
			SN54AS74A		SN74AS74A		
			MIN	MAX	MIN	MAX	
f_{max}			90		105		MHz
t_{PLH}	$\overline{PRE}$ or $\overline{CLR}$	Q or $\overline{Q}$	3	8.5	3	7.5	ns
t_{PHL}			3.5	11.5	3.5	10.5	
t_{PLH}	CLK	Q or $\overline{Q}$	3.5	9	3.5	8	ns
t_{PHL}			4.5	10.5	4.5	9	

§ For conditions shown MIN or MAX, use the appropriate value specified under recommended operating conditions.
NOTE 2: Load circuit and voltage waveforms are shown in Section 1 of the *ALS/AS Logic Data Book*, 1986.

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